



Imale

2878

PATENT

Case Docket No. IMEC222.001AUS

Date: February 23, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Hantschel, et al.  
Appl. No. : 09/955,565  
Filed : September 12, 2001  
For : PROBE TIP AND METHOD OF  
MANUFACTURING PROBE  
TIPS BY PEEL-OFF (As  
Amended)  
Group Art Unit : 2878

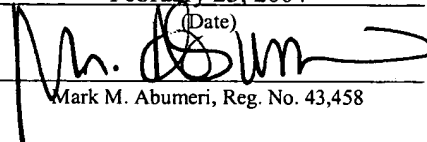
Class/Sub-Class: 250-234000

Examiner: Luu, Thanh X.

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

February 23, 2004

(Date)



Mark M. Abumeri, Reg. No. 43,458

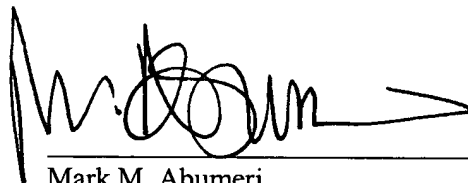
TRANSMITTAL LETTER

Commissioner for Patents  
P.O. Box 1450, Alexandria, VA 22313-1450

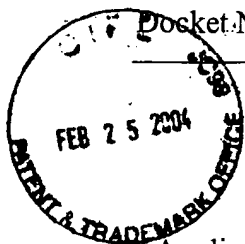
Dear Sir:

Enclosed for filing in the above-identified application are:

- (X) An Information Disclosure Statement.
- (X) A PTO Form 1449 with eight (8) references.
- (X) The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.
- (X) Return prepaid postcard.



Mark M. Abumeri  
Registration No. 43,458  
Attorney of Record  
Customer No. 20,995  
(619) 235-8550



Pocket No.:

Customer No. 20,995

### INFORMATION DISCLOSURE STATEMENT

Applicant(s) : Hantschel, et al.  
Appl. No. : 09/955,565  
Filed : September 12, 2001  
For : PROBE TIP AND METHOD OF  
MANUFACTURING PROBE TIPS BY  
PEEL-OFF (As Amended)  
Group Art Unit : 2878  
Class/Sub-Class: 250-234000  
Examiner: Luu, Thanh X.

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is form PTO-1449 listing eight (8) references that are also enclosed.

Please place these references in the file of the above-identified patent application in accordance with 37 C.F.R. § 1.97(i).

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: February 23, 2004

By: 

Mark M. Abumeri  
Registration No. 43,458  
Attorney of Record  
Customer No. 20,995  
(619) 235-8550

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE <b>INFORMATION DISCLOSURE STATEMENT          BY APPLICANT</b> (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. IMEC222.001AUS	APPLICATION NO. 09/955,565
	APPLICANT Hantschel, et al.	
	FILING DATE September 12, 2001	GROUP 2878

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	1.	6,291,140	09/18/01	Andreoli, et al.			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
							WITH ENGLISH ABSTRACT ONLY	
	2.	EP 1 202 047 A1	05/02/02	EUROPE			X	
	3.	JP 10-246729	09/14/98	JAPAN			X**	
	4.	WO 99/56176	11/04/99	PCT			X	

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
	5.	Hantschel, et al., "Highly conductive diamond probes for scanning spreading resistance microscopy", Applied Physics Letters, vol. 76, no. 12, pp. 1603-1605, (March 20, 2000).
	6.	Hantschel, et al., "Mounting of moulded AFM probes by soldering", Materials and Device Characterization in Micromachining III, Proceedings of SPIE, vol. 4175, pp. 62-73, (2000).
	7.	"Conference Materials and Device Characterization in Micromachining III", Proceedings of SPIE, vol. 4175, pp. 1-4, URL: <a href="http://spie.org/web/meetings/programs/mf00/confs/4175.html">http://spie.org/web/meetings/programs/mf00/confs/4175.html</a> (retrieved December 17, 2003).
	8.	European Search Report dated December 17, 2003, for European Application No. EP 01 87 0192.

S:\DOCS\MMA\MMA-8057.DOC/cfg/022304

EXAMINER	DATE CONSIDERED
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	